

Notic of References Cit d	Application/Control No. 10/682,440	Applicant(s)/Pat nt Under Reexamination YAMAZAKI ET AL.	
	Examiner Long K. Tran	Art Unit 2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,632,695	10-2003	Beierlein, Tilman A.	438/29
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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